Power MOSFET 30 V, 57 A, Single N–Channel, SO–8 FL

Features

- Low R_{DS(on)} to Minimize Conduction Losses
- Low Capacitance to Minimize Driver Losses
- Optimized Gate Charge to Minimize Switching Losses
- These are Pb–Free Device

Applications

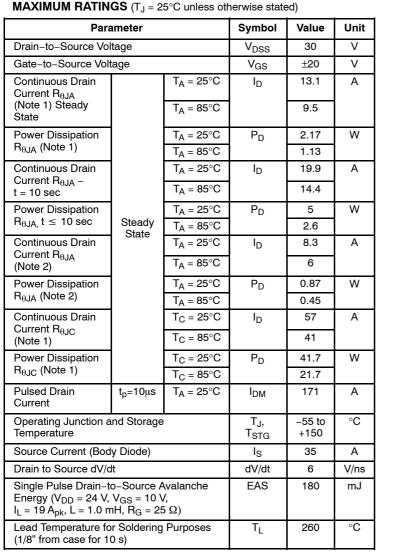
- Refer to Application Note AND8195/D
- CPU Power Delivery
- DC-DC Converters

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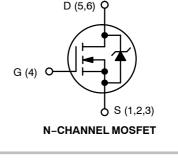
ON Semiconductor®

http://onsemi.com

V _{(BR)DSS}	R _{DS(ON)} MAX	I _D MAX
30 V	7.0 m Ω @ 10 V	57 A
50 V	11.4 m Ω @ 4.5 V	57 A



Stresses exceeding Maximum Ratings may damage the device. Maximum Ratings are stress ratings only. Functional operation above the Recommended Operating Conditions is not implied. Extended exposure to stresses above the Recommended Operating Conditions may affect device reliability.





ORDERING INFORMATION

Device	Package	Shipping [†]
NTMFS4841NT1G	SO-8FL (Pb-Free)	1500 / Tape & Reel
NTMFS4841NT3G	SO-8FL (Pb-Free)	5000 / Tape & Reel

†For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

*For additional information on our Pb–Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

THERMAL RESISTANCE MAXIMUM RATINGS

Parameter	Symbol	Value	Unit
Junction-to-Case (Drain)	$R_{\theta JC}$	3	
Junction-to-Ambient - Steady State (Note 1)	$R_{\theta JA}$	57.7	°C/W
Junction-to-Ambient - Steady State (Note 2)	$R_{\theta JA}$	143.4	-C/W
Junction-to-Ambient - t = 10 sec	$R_{ hetaJA}$	25	

Surface-mounted on FR4 board using 1 sq-in pad, 1 oz Cu.
Surface-mounted on FR4 board using the minimum recommended pad size.

ELECTRICAL CHARACTERISTICS (T_J = $25^{\circ}C$ unless otherwise specified)

Parameter	Symbol	Test Condition		Min	Тур	Max	Unit
OFF CHARACTERISTICS							
Drain-to-Source Breakdown Voltage	V _{(BR)DSS}	$V_{GS} = 0 \text{ V}, \text{ I}_{D} = 250 \ \mu\text{A}$		30			V
Drain-to-Source Breakdown Voltage Temperature Coefficient	V _{(BR)DSS} / T _J				25		mV/°C
Zero Gate Voltage Drain Current	I _{DSS}	$V_{GS} = 0 V,$	T _J = 25 °C			1	
		V _{DS} = 24 V	T _J = 125°C			10	μA
Gate-to-Source Leakage Current	I _{GSS}	V_{DS} = 0 V, V_{GS} = ±20 V				±100	nA
ON CHARACTERISTICS (Note 3)							
Gate Threshold Voltage	V _{GS(TH)}	V _{GS} = V _{DS} , I _D =	= 250 μA	1.5		2.5	V
Negative Threshold Temperature Coefficient	V _{GS(TH)} /T _J				5.6		mV/°C
Drain-to-Source On Resistance	R _{DS(on)}	$V_{GS} = 10 \text{ V to}$	I _D = 30 A		4.7	7.0	
		11.5 V	I _D = 15 A		4.6		0
		V _{GS} = 4.5 V	I _D = 30 A		9.2	11.4	mΩ
			I _D = 15 A		8.5		
Forward Transconductance	9 FS	V _{DS} = 15 V, I _D = 15 A			16		S
CHARGES AND CAPACITANCES							
Input Capacitance	C _{ISS}				1436		
Output Capacitance	C _{OSS}	V_{GS} = 0 V, f = 1 MHz, V_{DS} = 12 V			348		pF
Reverse Transfer Capacitance	C _{RSS}				177		
Total Gate Charge	Q _{G(TOT)}				11.5	17	
Threshold Gate Charge	Q _{G(TH)}				2.0		
Gate-to-Source Charge	Q _{GS}	V _{GS} = 4.5 V, V _{DS} = 15 V; I _D = 30 A			5.0		nC

Total Gate Charge

Gate-to-Drain Charge

SWITCHING CHARACTERISTICS (Note 4)

Turn-On Delay Time	t _{d(ON)}		13.5	
Rise Time	t _r	V _{GS} = 4.5 V, V _{DS} = 15 V, I _D = 15 A,	66.5	20
Turn-Off Delay Time	t _{d(OFF)}	R _G = 3.0 Ω	15.5	ns
Fall Time	t _f		7.5	

Q_{GD}

Q_{G(TOT)}

5.1

25.4

nC

3. Pulse Test: pulse width \leq 300 μ s, duty cycle \leq 2%.

4. Switching characteristics are independent of operating junction temperatures.

ELECTRICAL CHARACTERISTICS (T_J = 25° C unless otherwise specified)

Parameter	Symbol	Test Condition		Min	Тур	Max	Unit
SWITCHING CHARACTERISTICS (N	ote 4)			-	-		
Turn-On Delay Time	t _{d(ON)}	V_{GS} = 11.5 V, V_{DS} = 15 V, I _D = 15 A, R _G = 3.0 Ω			8.1		ns
Rise Time	t _r				24.2		
Turn-Off Delay Time	t _{d(OFF)}				22.8		
Fall Time	t _f				5.7		
DRAIN-SOURCE DIODE CHARACT	ERISTICS						
Forward Diode Voltage	V _{SD}	$V_{GS} = 0 V,$ $T_J = 25^{\circ}C$		0.9	1.2	v	
		$I_{\rm S} = 30 {\rm A}$ $T_{\rm J} = 125^{\circ}{\rm C}$			0.8		
Reverse Recovery Time	t _{RR}	V _{GS} = 0 V, dI _S /dt = 100 A/µs, I _S = 30 A			20.5		ns
Charge Time	t _a				11.6		
Discharge Time	t _b				8.9		
Reverse Recovery Charge	Q _{RR}				10.7		nC
PACKAGE PARASITIC VALUES							
Source Inductance	L _S				0.93		nH
Drain Inductance	L _D	- T _A = 25°C			0.005		
Gate Inductance	L _G				1.84		

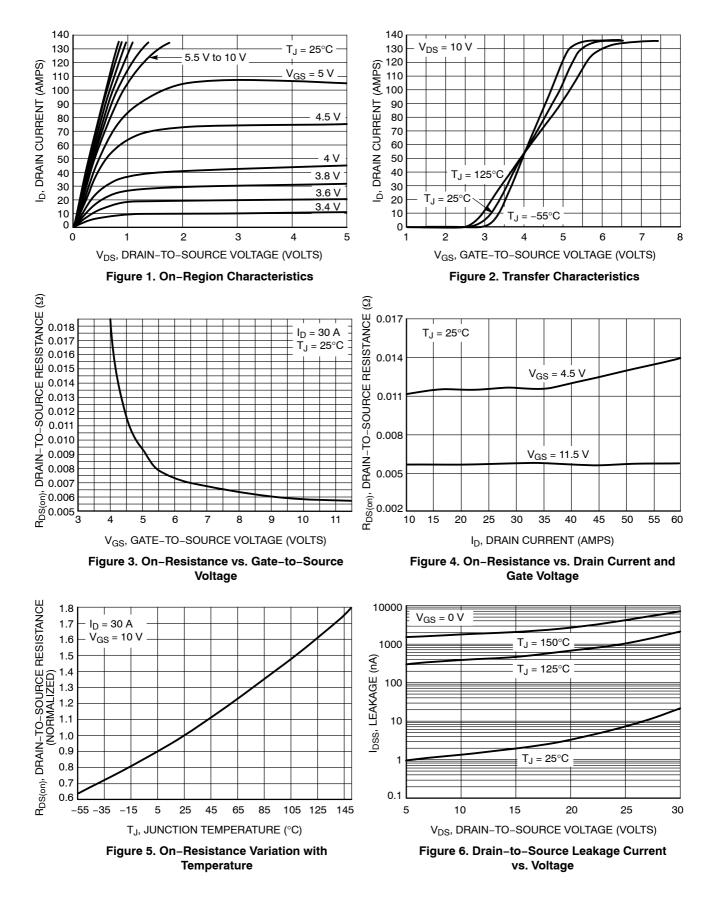
3.2

Ω

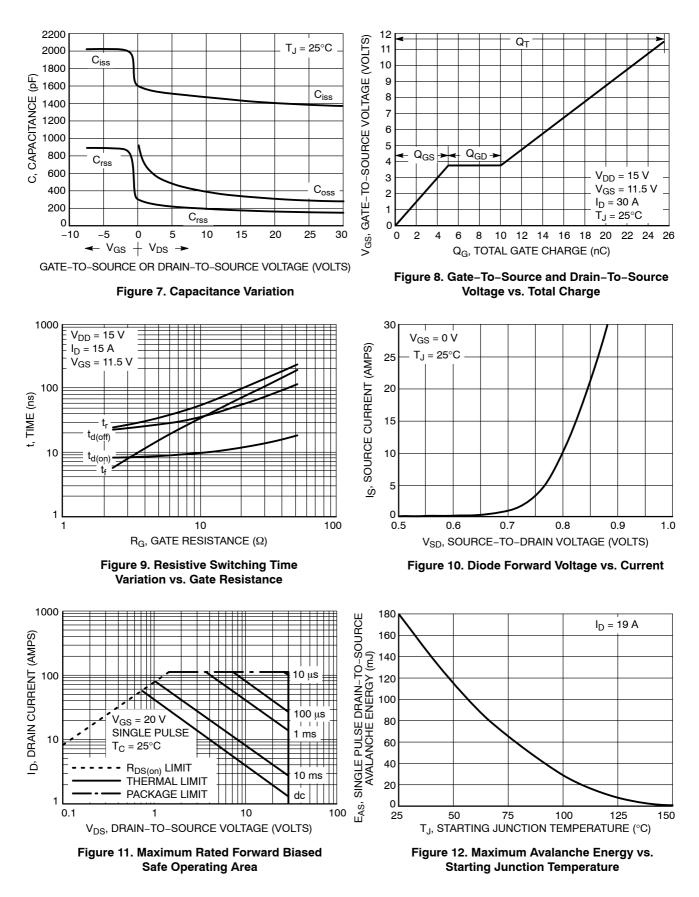
Gate Resistance

 R_G

TYPICAL PERFORMANCE CURVES



TYPICAL PERFORMANCE CURVES



TYPICAL PERFORMANCE CURVES

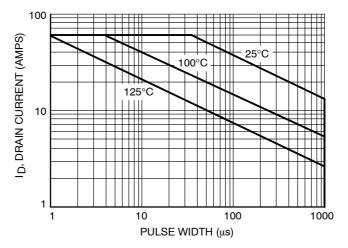


Figure 13. EAS vs. Pulse Width

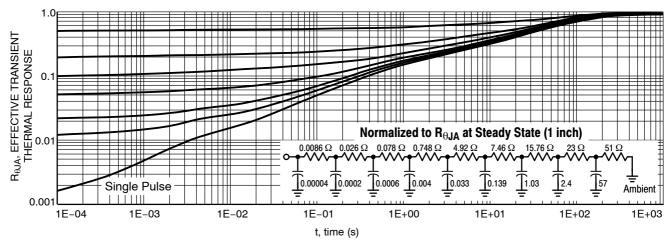
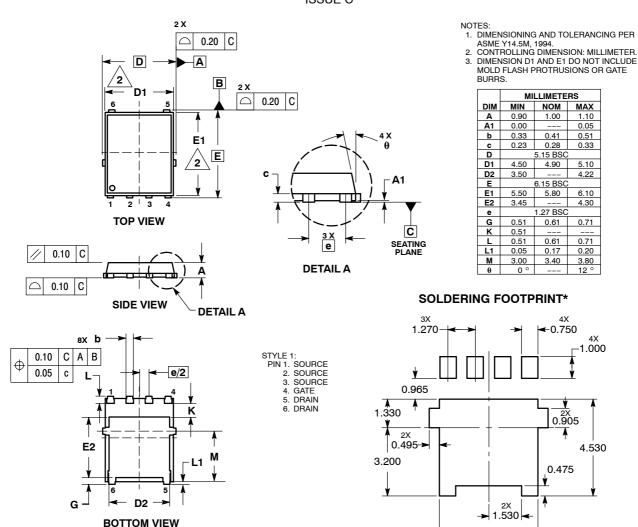


Figure 14. FET Thermal Response

PACKAGE DIMENSIONS

DFN6 5x6, 1.27P (SO8 FL) CASE 488AA-01 ISSUE C



*For additional information on our Pb–Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

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